Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/646,651	ZWADLO ET AL.
Examiner	Art Unit
Hai C. Pham	2861

SEARCHED				
Class	Subclass	Date	Examiner	
347	234, 241, 244, 248, 256, 258	4/16/2005	HP	
430	30, 201	4/16/2005	HP	
-				

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
-			
	<u> </u>	 	

		DATE	EXMR
· · · · · · · · · · · · · · · · · · ·		•	
east		4/16/2005	НР
	•		
		•	